

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination BABIRZ ET AL.	
		Examiner Raj K. Jain	Art Unit 2616	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0192312	09-2004	Li et al.	455/445
*	B	US-6,622,172	09-2003	Tam, Ming-Chit	709/232
	C	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	An ECN Probe-BASED Connection Acceptance Control , Jul 2001, Tom Kelly
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.